


<b>Search Notes</b>  	<b>Application/Control No.</b>  10782779	<b>Applicant(s)/Patent Under Reexamination</b>  OWASHI ET AL.
	<b>Examiner</b>  Debelie, Mitiku	<b>Art Unit</b>  2621

### SEARCHED

Class	Subclass	Date	Examiner
386	46	8/30/2007	MD
386	83	3/24/2008	MD
360	79	3/24/2008	MD
348	5,5,6,10,11,731	3/24/2008	MD

### SEARCH NOTES

Search Notes	Date	Examiner
Inventor search	8/28/2007	MD
consulted Thai Tran about prior art	8/24/2008	MD

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner